

Reliability data to support PCN 12_0285, ADF4350A

QUALIFICATION RESULTS			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)*	JEDEC <i>JESD22-A108</i>	3x77 1x45 4x45 2x45	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	2x77 3x77 2x77 2x45	Pass
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	3x77 1x77 2x77 1x45 2x32	Pass
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	3x77 2x32 1x45 2x45 1x77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	3x45 1x45 1x77 6x32	Pass
Latch-Up	JEDEC <i>JESD78</i>	6	Pass
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JDS-001-2011</i>	3/voltage	Pass 3000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass 1500V

*Preconditioned per JEDEC/IPC J-STD-020